

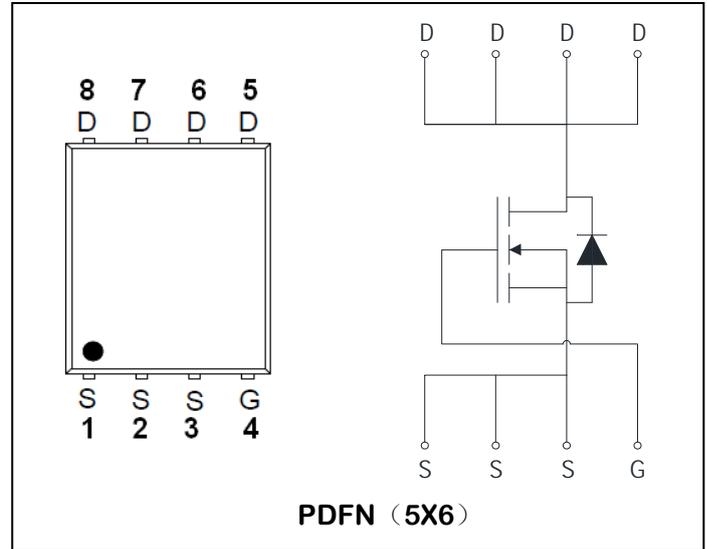
N-Channel Enhancement Mode Field Effect Transistor

PRODUCT SUMMARY

V_{DSS}	I_D	$R_{DS(ON)}$ (m Ω)
100V	55A	9m Ω

Features:

- Low Gate Charge for Fast Switching Application
- Low $R_{DS(ON)}$ to Minimize Conductive Loss
- 100% EAS Guaranteed
- Optimized $V_{(BR)DSS}$ Ruggedness
- Lead-Free, RoHS Compliant



Description:

The ADM75N10Q uses advanced trench technology and design to provide excellent $R_{DS(ON)}$ with low gate charge. It can be used in a wide variety of applications.

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter		Ratings	Unit
Common Ratings				
V_{DSS}	Drain-Source Voltage		100	V
V_{GSS}	Gate-Source Voltage		+20/-12	
T_J	Maximum Junction Temperature		150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range		-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C = 25^\circ\text{C}$	55	A
Mounted on Large Heat Sink				
I_{DM}	300 μs Pulse Drain Current Tested ⁽²⁾	$T_C = 25^\circ\text{C}$	200	A
I_D	Continuous Drain Current ⁽¹⁾	$T_C = 25^\circ\text{C}$	55	A
		$T_C = 100^\circ\text{C}$	38	A
P_D	Maximum Power Dissipation	$T_A = 25^\circ\text{C}$	3.1	W

Thermal Characteristics

Symbol	Parameter	Ratings	Unit
R_{thJC}	Thermal resistance junction-case max ⁽¹⁾	2.3	$^\circ\text{C}/\text{W}$
R_{thJA}	Thermal resistance junction-ambient max ⁽¹⁾	70	$^\circ\text{C}/\text{W}$

Electrical Characteristics (T_A=25°C Unless Otherwise Noted)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
On/off Characteristics						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =250uA	100	--	--	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =100V, V _{GS} =0V , T _J =25°C	--	--	1	uA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =250uA	1	1.8	2.5	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	--	--	±100	nA
R _{DS(ON)}	Drain-Source On-state Resistance ⁽²⁾	V _{GS} = 10V, I _{DS} =14A	--	9	12	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{GS} =0V,	--	3350	--	pF
C _{oss}	Output Capacitance	V _{DS} =50V,	--	270	--	
C _{rss}	Reverse Transfer Capacitance	Frequency=1MHz	--	15	--	
Switching Characteristics						
t _{d(ON)}	Turn-on Delay Time	V _{DS} =50V,	--	10	--	nS
t _r	Turn-on Rise Time	I _D = 14A, V _{GS} = 10V,	--	5	--	
t _{d(OFF)}	Turn-off Delay Time	R _{GEN} =10 Ω	--	32	--	
t _f	Turn-off Fall Time		--	6	--	
Q _g	Total Gate Charge	V _{DS} =50V, V _{GS} = 10V,	--	49	--	nC
Q _{gs}	Gate-Source Charge	I _{DS} =14A	--	8	--	
Q _{gd}	Gate-Drain Charge		--	7	--	
Avalanche Characteristics						
EAS	Single Pulse Avalanche Energy ⁽³⁾	L=0.1mH , T _C =25°C	80	--	--	mJ
Diode Characteristics						
V _{SD}	Diode Forward Voltage ⁽²⁾	I _{SD} = 14A, V _{GS} = 0	--	0.9	1.2	V
t _{rr}	Reverse Recovery Time	I _{SD} =14A, dI _{SD} /dt=100A/μs	--	47	--	ns
q _{rr}	Reverse Recovery Charge		--	226	--	nC

NOTES:

1. Surface Mounted on FR4 Board, t ≤ 10 sec.
2. The data tested by pulsed , pulse width ≤ 300us , duty cycle ≤ 2%
3. The Min. value is 100% EAS tested guarantee.

Typical Performance Characteristics

Figure 1: On-Region Characteristics

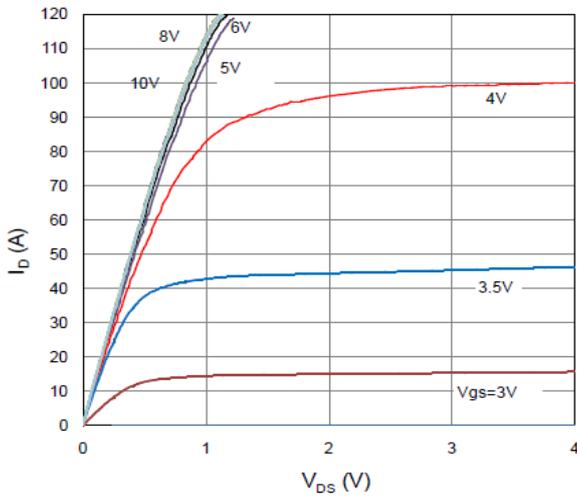


Figure 2: Transfer Characteristics

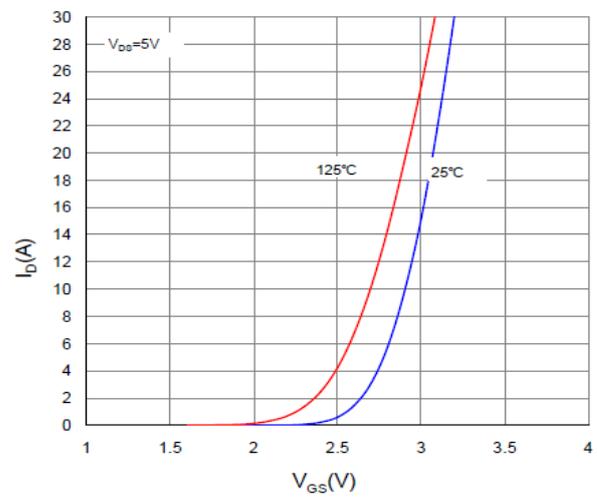


Figure 3: R_{DS(on)}- Drain Current

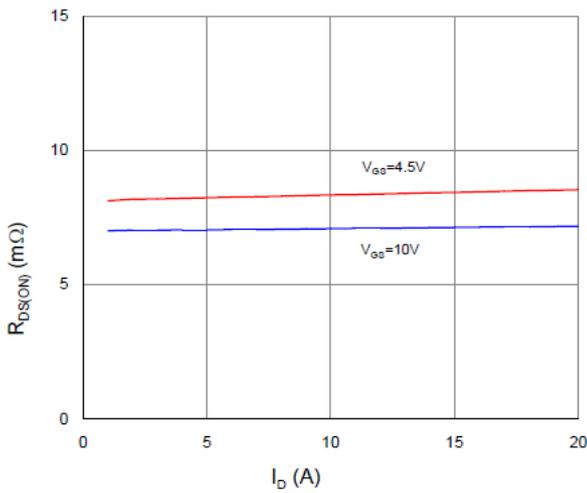


Figure 4: R_{DS(on)}-Junction Temperature

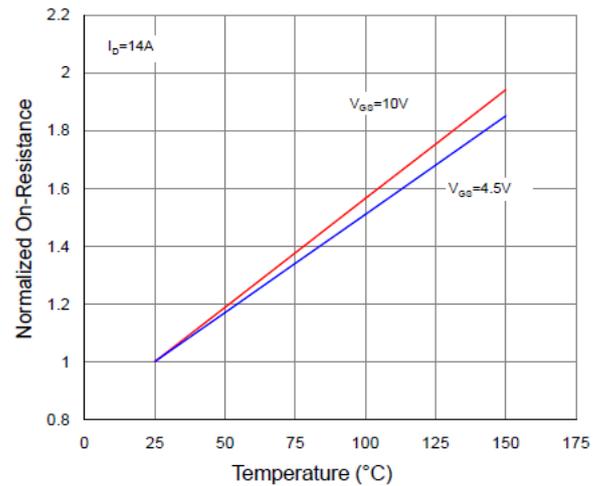


Figure 5: Source- Drain Diode Forward

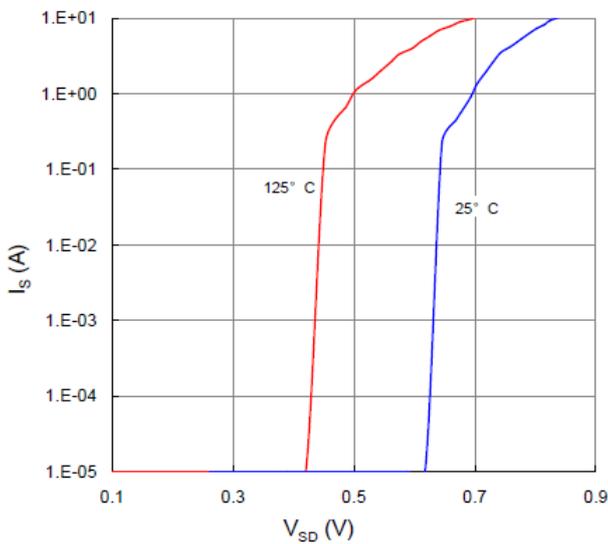


Figure 6: Gate Charge Characteristics

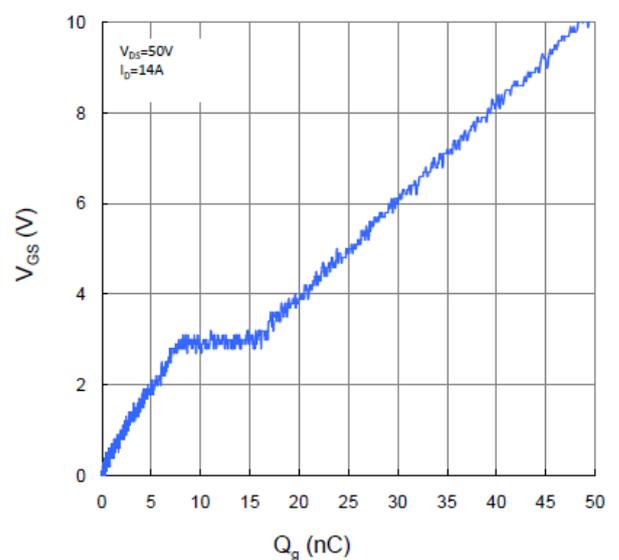


Figure 7: Capacitance vs Vds

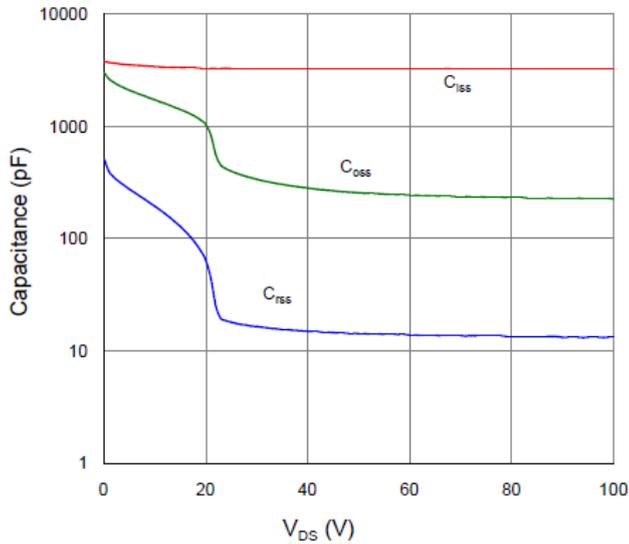


Figure 8: Safe Operation Area

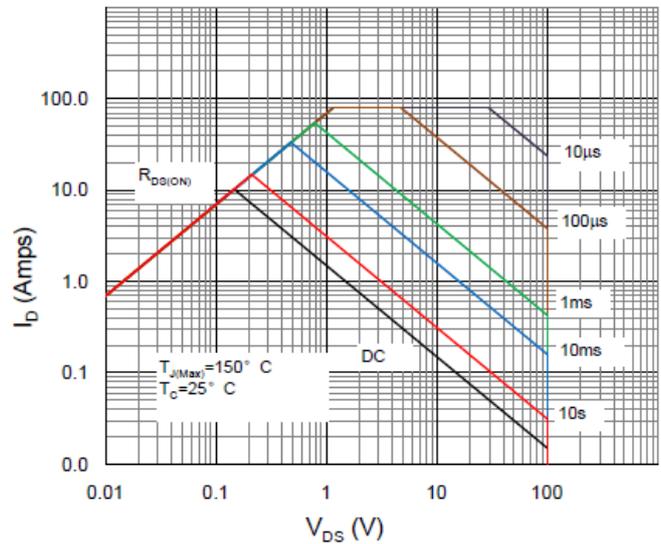


Figure 9: Maximum Drain Current vs. Case Temperature

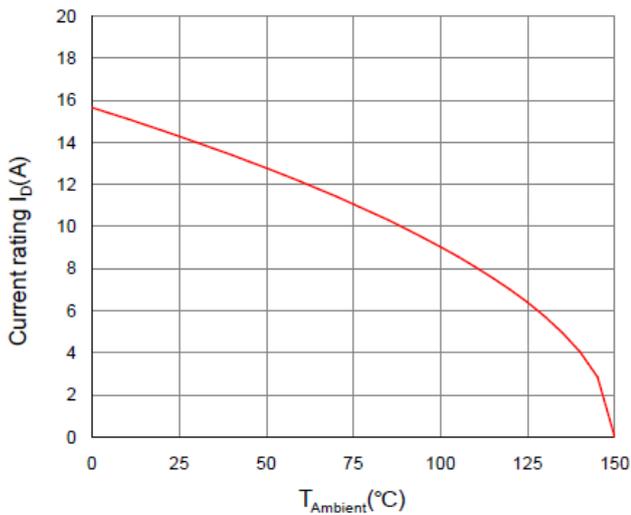


Figure 10: On-Resistance vs. Gate-Source Voltage

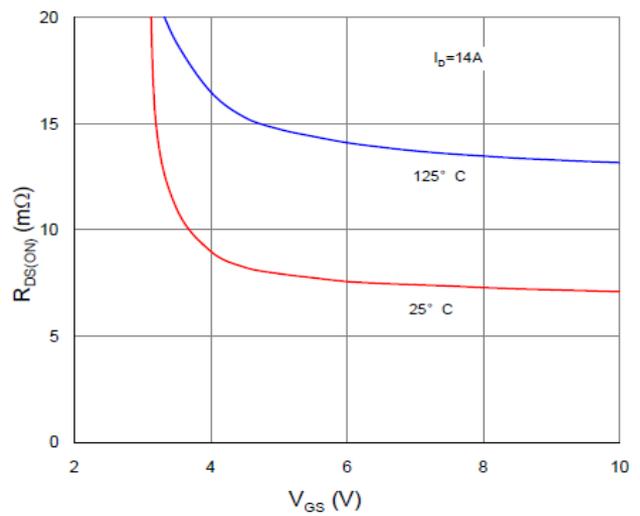
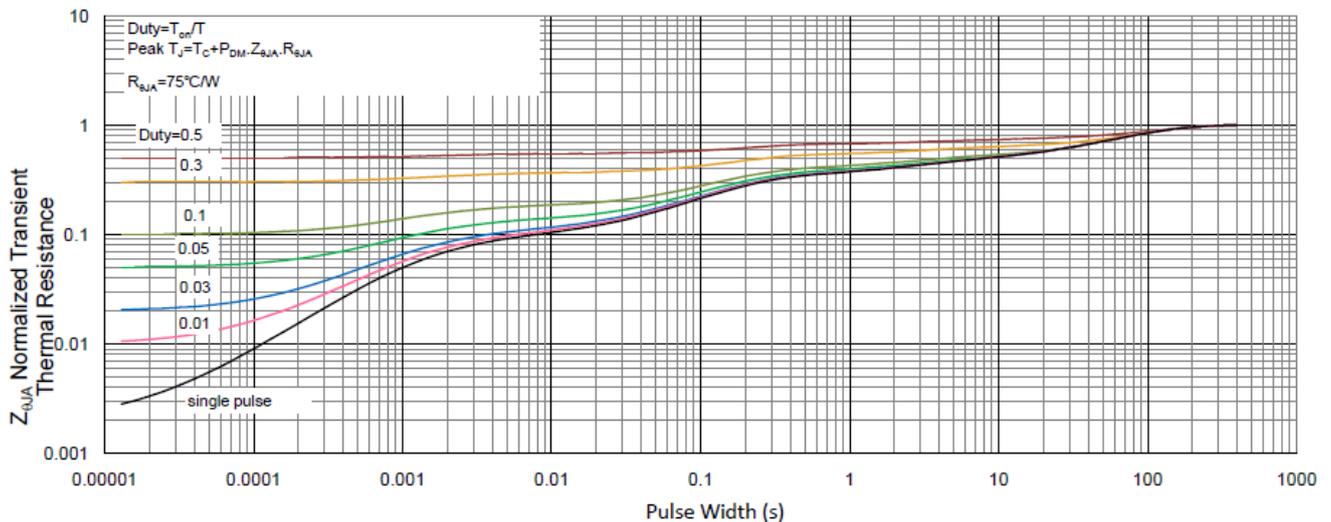
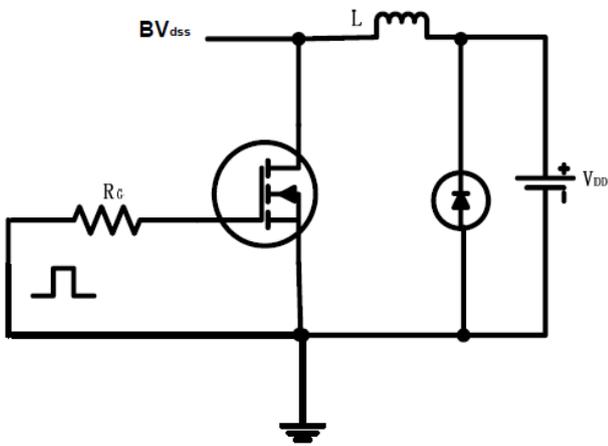


Figure 11: Normalized Maximum Transient Thermal Impedance

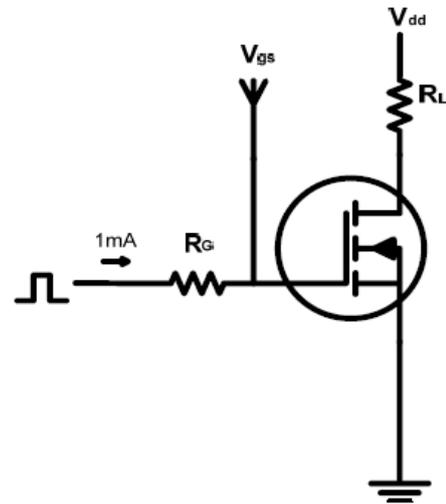


Test circuits and Waveforms

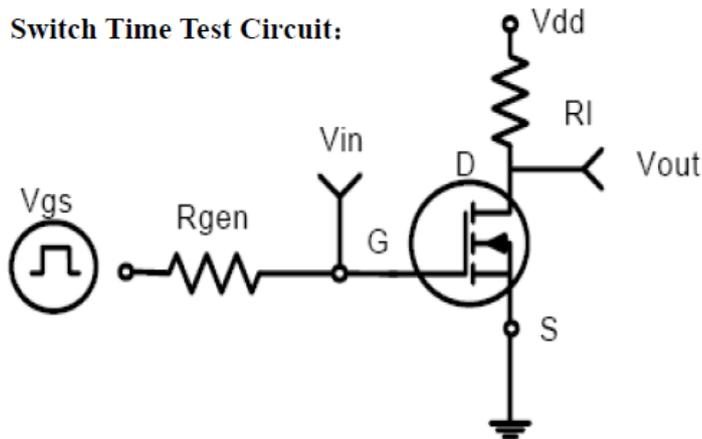
EAS test circuits:



Gate charge test circuit:



Switch Time Test Circuit:



Switch Waveforms:

